

Search Notes

Application/Control No.

10/785,259

Examiner

B. Chen

Applicant(s)/Patent under
Reexamination

OHKAWA ET AL.

Art Unit

1762

SEARCHED

Class	Subclass	Date	Examiner
updated	previous	11/6/2006	BC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
427	255.29	11/6/2006	BC
427	255.31	11/6/2006	BC
427	376.2	11/6/2006	BC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	11/6/2006	BC